Very Low Power/Voltage CMOS SRAM
64K X 16 bit

BS616LV1013

■ FEATURES

- Very low operation voltage : 2.7 ~ 3.6V
- Very low power consumption :

  Vcc = 3.0V C-grade : 20mA (Max.) operating current
  I-grade : 25mA (Max.) operating current
  0.02uA (Typ.) CMOS standby current

High speed access time :

  -70 70ns (Max.) at Vcc = 3.0V

- Automatic power down when chip is deselected
- Three state outputs and TTL compatible
- Fully static operation
- Data retention supply voltage as low as 1.5V
- Easy expansion with $\overline{CE}$ and $\overline{OE}$ options
- I/O Configuration x8/x16 selectable by $\overline{LB}$ and $\overline{UB}$ pin

■ DESCRIPTION

The BS616LV1013 is a high performance, very low power CMOS Static Random Access Memory organized as 65,536 words by 16 bits and operates from a wide range of 2.7V to 3.6V supply voltage.

Advanced CMOS technology and circuit techniques provide both high speed and low power features with a typical CMOS standby current of 0.02uA and maximum access time of 70ns in 3.0V operation.

Easy memory expansion is provided by an active LOW chip enable($\overline{CE}$) and active LOW output enable($\overline{OE}$) and three-state output drivers.

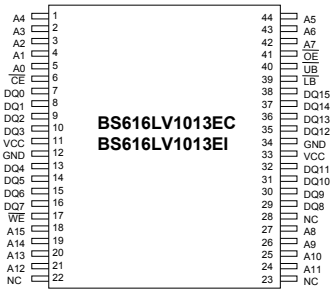
The BS616LV1013 has an automatic power down feature, reducing the power consumption significantly when chip is deselected.

The BS616LV1013 is available in the JEDEC standard 44-pin TSOP Type II and 48-pin BGA package.

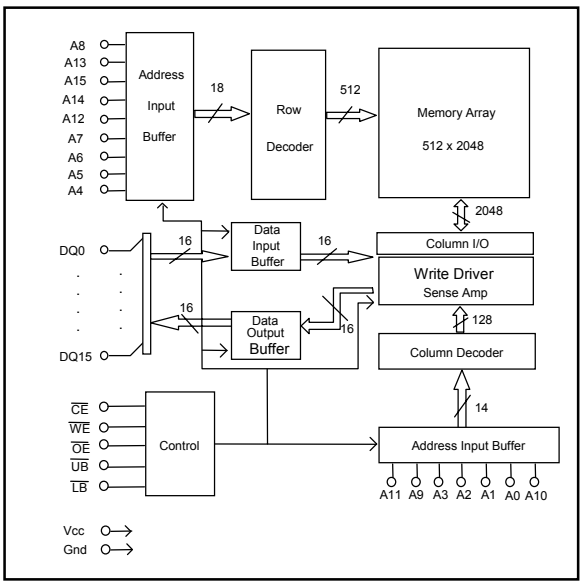
■ PRODUCT FAMILY

PRODUCT FAMILY	OPERATING TEMPERATURE	Vcc RANGE	SPEED (ns)	POWER DISSIPATION		PKG TYPE
				STANDBY (I_{CCSB1}, Max)	Operating (I_{CC}, Max)	
			Vcc=3.0V	Vcc=3.0 V	Vcc=3.0 V	
BS616LV1013EC	+0°C to +70°C	2.7V ~ 3.6V	70	0.5uA	20mA	TSOP2-44
BS616LV1013AC						BGA-48-0608
BS616LV1013EI	-40°C to +85°C	2.7V ~ 3.6V	70	1.5uA	25mA	TSOP2-44
BS616LV1013AI						BGA-48-0608

■ PIN CONFIGURATIONS



■ BLOCK DIAGRAM



■ PIN DESCRIPTIONS

Name	Function
A0-A15 Address Input	These 16 address inputs select one of the 65,536 x 16-bit words in the RAM.
$\overline{CE}$ Chip Enable Input	$\overline{CE}$ is active LOW. Chip enables must be active when data read from or write to the device. if chip enable is not active, the device is deselected and is in a standby power mode. The DQ pins will be in the high impedance state when the device is deselected.
$\overline{WE}$ Write Enable Input	The write enable input is active LOW and controls read and write operations. With the chip selected, when $\overline{WE}$ is HIGH and $\overline{OE}$ is LOW, output data will be present on the DQ pins; when $\overline{WE}$ is LOW, the data present on the DQ pins will be written into the selected memory location.
$\overline{OE}$ Output Enable Input	The output enable input is active LOW. If the output enable is active while the chip is selected and the write enable is inactive, data will be present on the DQ pins and they will be enabled. The DQ pins will be in the high impedance state when $\overline{OE}$ is inactive.
$\overline{LB}$ and $\overline{UB}$ Data Byte Control Input	Lower byte and upper byte data input/output control pins.
DQ0 - DQ15 Data Input/Output Ports	These 16 bi-directional ports are used to read data from or write data into the RAM.
Vcc	Power Supply
Gnd	Ground

■ TRUTH TABLE

MODE	$\overline{CE}$	$\overline{WE}$	$\overline{OE}$	$\overline{LB}$	$\overline{UB}$	DQ0~DQ7	DQ8~DQ15	Vcc CURRENT
Not selected (Power Down)	H	X	X	X	X	High Z	High Z	I_{CCSB}, I_{CCSB1}
Output Disabled	L	H	H	X	X	High Z	High Z	I_{CC}
Read	L	H	L	L	L	Dout	Dout	I_{CC}
				H	L	High Z	Dout	I_{CC}
				L	H	Dout	High Z	I_{CC}
Write	L	L	X	L	L	Din	Din	I_{CC}
				H	L	X	Din	I_{CC}
				L	H	Din	X	I_{CC}

■ ABSOLUTE MAXIMUM RATINGS(1)

SYMBOL	PARAMETER	RATING	UNITS
VTERM	Terminal Voltage with Respect to GND	-0.5 to Vcc+0.5	V
TBIAS	Temperature Under Bias	-40 to +125	°C
TSTG	Storage Temperature	-60 to +150	°C
PT	Power Dissipation	1.0	W
IOUT	DC Output Current	20	mA

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

■ OPERATING RANGE

RANGE	AMBIENT TEMPERATURE	Vcc
Commercial	0°C to +70°C	2.7V ~ 3.6V
Industrial	-40°C to +85°C	2.7V ~ 3.6V

■ CAPACITANCE (1) (TA = 25°C, f = 1.0 MHz)

SYMBOL	PARAMETER	CONDITIONS	MAX.	UNIT
CIN	Input Capacitance	VIN=0V	6	pF
CDQ	Input/Output Capacitance	VI/O=0V	8	pF

1. This parameter is guaranteed and not 100% tested.

■ DC ELECTRICAL CHARACTERISTICS (TA = 0°C to + 70°C)

PARAMETER NAME	PARAMETER	TEST CONDITIONS		MIN.	TYP. (1)	MAX.	UNITS
VIL	Guaranteed Input Low Voltage(2)		Vcc=3.0V	-0.5	--	0.8	V
VIH	Guaranteed Input High Voltage(2)		Vcc=3.0V	2.0	--	Vcc+0.2	V
IIL	Input Leakage Current	Vcc = Max, VIN = 0V to Vcc		--	--	1	uA
ILO	Output Leakage Current	Vcc = Max, $\overline{CE}$ = VIH, or $\overline{OE}$ = VIH, VI/O = 0V to Vcc		--	--	1	uA
VOL	Output Low Voltage	Vcc = Max, IOL = 2mA	Vcc=3.0V	--	--	0.4	V
VOH	Output High Voltage	Vcc = Min, IOH = -1mA	Vcc=3.0V	2.4	--	--	V
ICC	Operating Power Supply Current	$\overline{CE}$ = VIL, IDQ = 0mA, F = Fmax(3)	Vcc=3.0V	--	--	20	mA
ICCSB	Standby Current-TTL	$\overline{CE}$ = VIH, IDQ = 0mA	Vcc=3.0V	--	--	1	mA
ICCSB1	Standby Current-CMOS	$\overline{CE} \geqq$ Vcc -0.2V, VIN $\geqq$ Vcc - 0.2V or VIN $\leqq$ 0.2V	Vcc=3.0V	--	0.02	0.5	uA

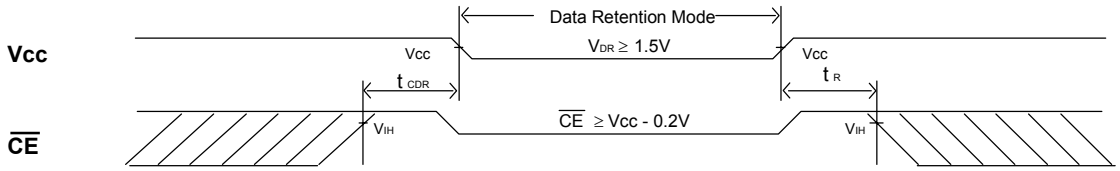
1. Typical characteristics are at TA = 25°C.
2. These are absolute values with respect to device ground and all overshoots due to system or tester notice are included.
3. Fmax = $1/t_{RC}$.

■ DATA RETENTION CHARACTERISTICS (TA = 0°C to + 70°C)

SYMBOL	PARAMETER	TEST CONDITIONS	MIN.	TYP. (1)	MAX.	UNITS
V_{DR}	Vcc for Data Retention	$\overline{CE} \geqq$ Vcc - 0.2V VIN $\geqq$ Vcc - 0.2V or VIN $\leqq$ 0.2V	1.5	--	--	V
I_{CCDR}	Data Retention Current	$\overline{CE} \geqq$ Vcc - 0.2V VIN $\geqq$ Vcc - 0.2V or VIN $\leqq$ 0.2V	--	0.02	0.3	uA
t_{CDR}	Chip Deselect to Data Retention Time	See Retention Waveform	0	--	--	ns
t_R	Operation Recovery Time		T_{RC} (2)	--	--	ns

1. Vcc = 1.5V, T_A = + 25°C
2. t_{RC} = Read Cycle Time

■ LOW V_{CC} DATA RETENTION WAVEFORM ($\overline{CE}$ Controlled)



■ AC TEST CONDITIONS

Input Pulse Levels	Vcc/0V
Input Rise and Fall Times	1V/ns
Input and Output Timing Reference Level	0.5Vcc

■ KEY TO SWITCHING WAVEFORMS

WAVEFORM	INPUTS	OUTPUTS
	MUST BE STEADY	MUST BE STEADY
	MAY CHANGE FROM H TO L	WILL BE CHANGE FROM H TO L
	MAY CHANGE FROM L TO H	WILL BE CHANGE FROM L TO H
	DON'T CARE: ANY CHANGE PERMITTED	CHANGE : STATE UNKNOWN
	DOES NOT APPLY	CENTER LINE IS HIGH IMPEDANCE "OFF "STATE

■ AC TEST LOADS AND WAVEFORMS

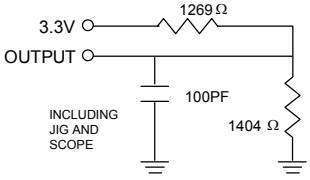


FIGURE 1A

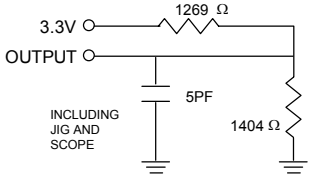
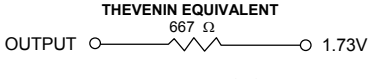


FIGURE 1B



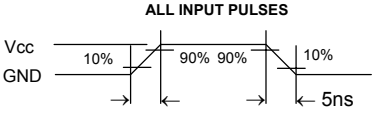


FIGURE 2

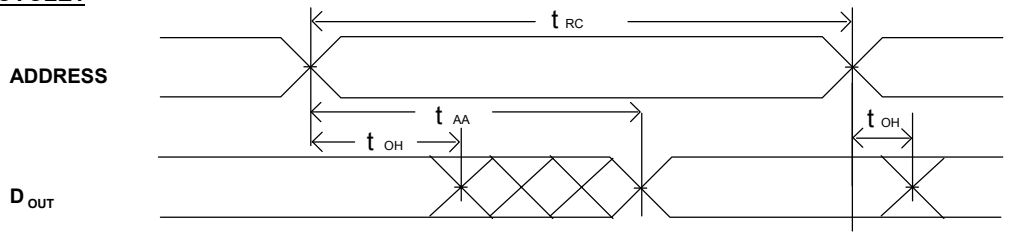
■ AC ELECTRICAL CHARACTERISTICS (TA = 0°C to + 70°C , Vcc = 3.0V)

READ CYCLE

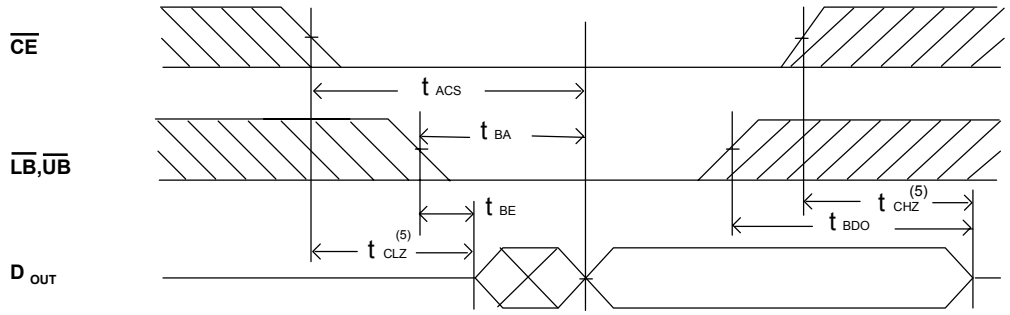
JEDEC PARAMETER NAME	PARAMETER NAME	DESCRIPTION	CYCLE TIME : 70ns MIN.	TYP.	MAX.	UNIT
t_{AVAX}	t_{RC}	Read Cycle Time	70	--	--	ns
t_{AVQV}	t_{AA}	Address Access Time	--	--	70	ns
t_{E1LQV}	t_{ACS}	Chip Select Access Time ($\overline{CE}$)	--	--	70	ns
t_{BA}	t_{BA}	Data Byte Control Access Time ($\overline{LB}$,$\overline{UB}$)	--	--	40	ns
t_{GLQV}	t_{OE}	Output Enable to Output Valid	--	--	50	ns
t_{E1LQX}	t_{CLZ}	Chip Select to Output Low Z ($\overline{CE}$)	10	--	--	ns
t_{BE}	t_{BE}	Data Byte Control to Output Low Z ($\overline{LB}$,$\overline{UB}$)	10	--	--	ns
t_{GLQX}	t_{OLZ}	Output Enable to Output in Low Z	10	--	--	ns
t_{E1HQZ}	t_{CHZ}	Chip Deselect to Output in High Z ($\overline{CE}$)	--	--	35	ns
t_{BDO}	t_{BDO}	Data Byte Control to Output High Z ($\overline{LB}$,$\overline{UB}$)	--	--	30	ns
t_{GHQZ}	t_{OHZ}	Output Disable to Output in High Z	--	--	30	ns
t_{AXOX}	t_{OH}	Data Hold from Address Change	10	--	--	ns

■ SWITCHING WAVEFORMS (READ CYCLE)

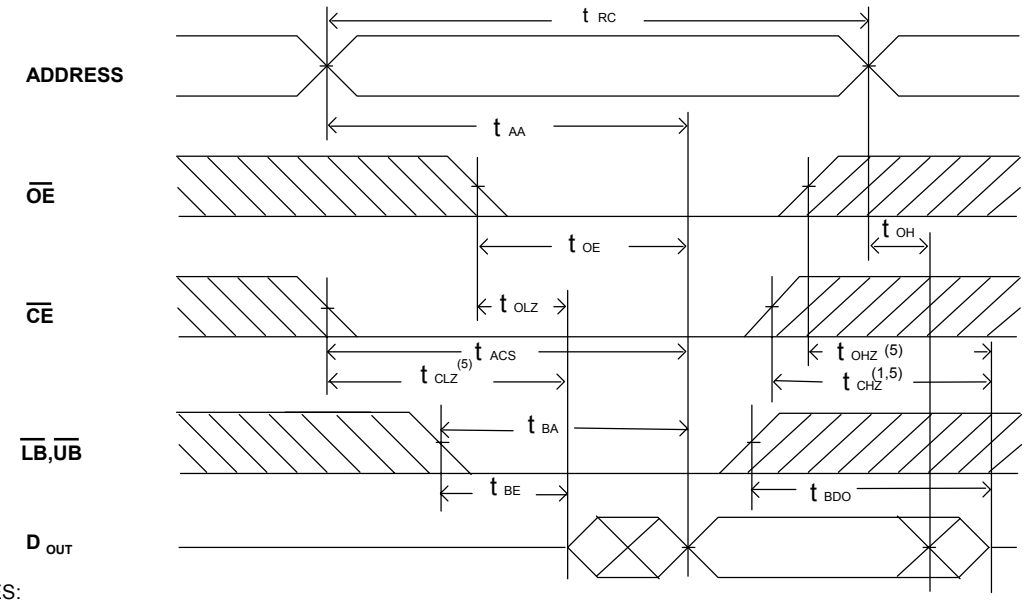
READ CYCLE1 (1,2,4)



READ CYCLE2 (1,3,4)



READ CYCLE3 (1,4)



NOTES:
1. $\overline{WE}$ is high for read Cycle.
2. Device is continuously selected when $\overline{CE}$ = V_{IL}.
3. Address valid prior to or coincident with $\overline{CE}$ transition low.
4. $\overline{OE}$ = V_{IL} .
5. Transition is measured ±500mV from steady state with C_L = 5pF as shown in Figure 1B. The parameter is guaranteed but not 100% tested.

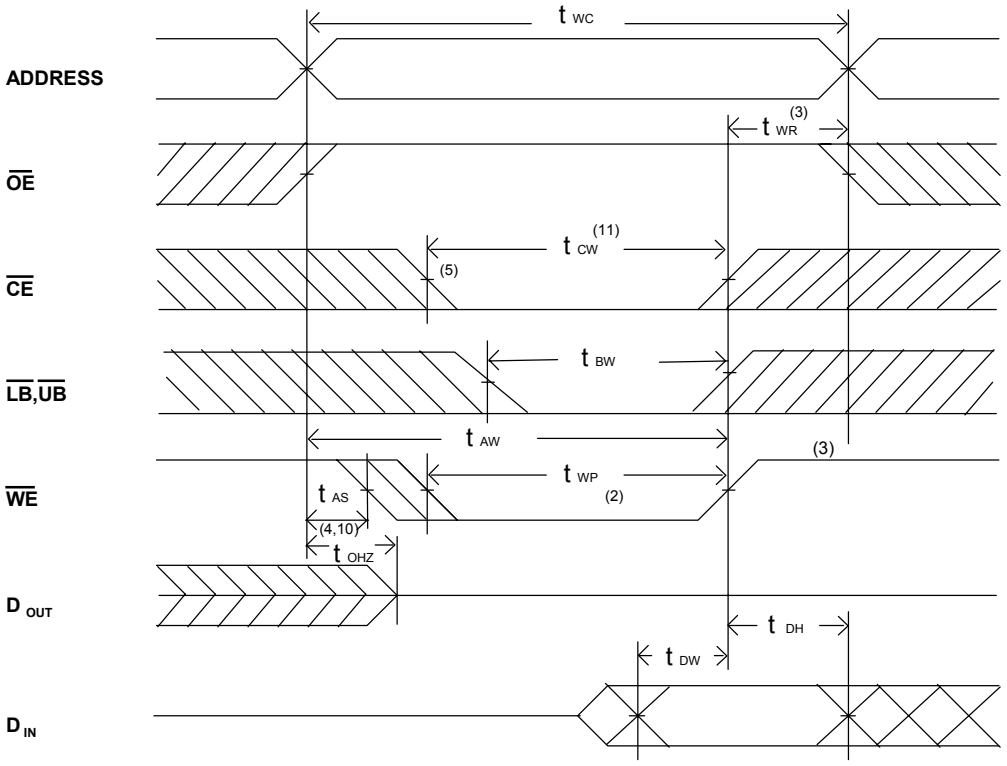
■ AC ELECTRICAL CHARACTERISTICS (TA = 0°C to + 70°C , Vcc = 3.0V)

WRITE CYCLE

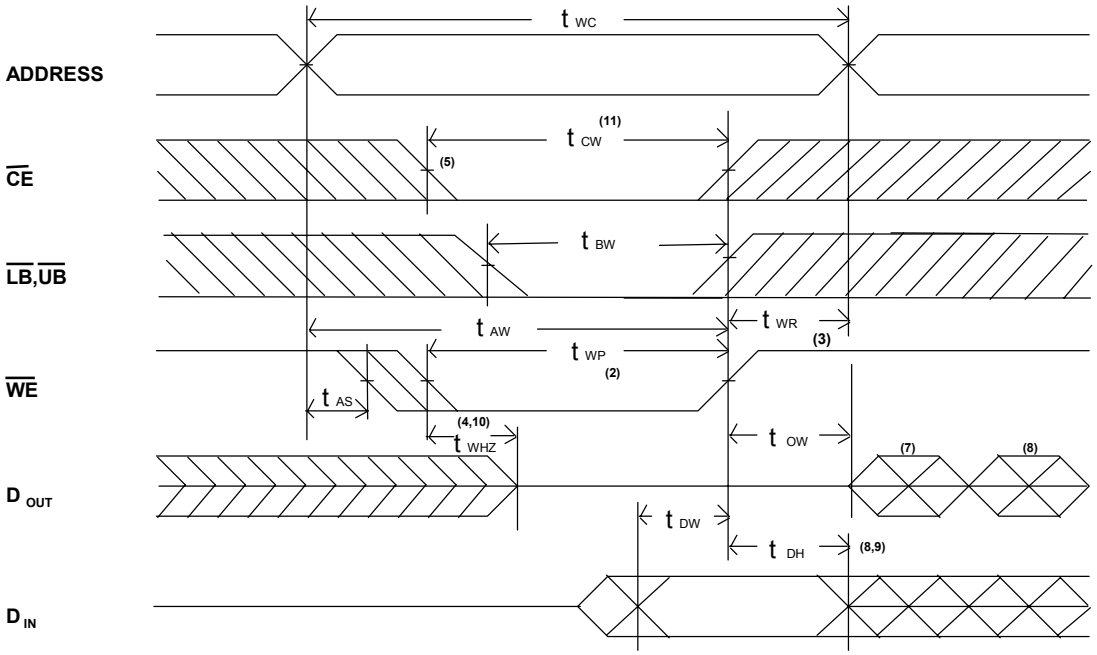
JEDEC PARAMETER NAME	PARAMETER NAME	DESCRIPTION	CYCLE TIME : 70ns MIN.	TYP.	MAX.	UNIT
t_{AVAX}	t_{WC}	Write Cycle Time	70	--	--	ns
t_{E1LWH}	t_{CW}	Chip Select to End of Write	70	--	--	ns
t_{AVWL}	t_{AS}	Address Setup Time	0	--	--	ns
t_{AVWH}	t_{AW}	Address Valid to End of Write	70	--	--	ns
t_{WLWH}	t_{WP}	Write Pulse Width	50	--	--	ns
t_{WHAX}	t_{WR}	Write recovery Time ($\overline{CE}$,$\overline{WE}$)	0	--	--	ns
t_{BW}	t_{BW}	Date Byte Control to End of Write ($\overline{LB}$,$\overline{UB}$)	60	--	--	ns
t_{WLQZ}	t_{WHZ}	Write to Output in High Z	--	--	30	ns
t_{DVWH}	t_{DW}	Data to Write Time Overlap	30	--	--	ns
t_{WHDX}	t_{DH}	Data Hold from Write Time	0	--	--	ns
t_{GHQZ}	t_{OHZ}	Output Disable to Output in High Z	--	--	30	ns
t_{WHOX}	t_{OW}	End of Write to Output Active	5	--	--	ns

■ SWITCHING WAVEFORMS (WRITE CYCLE)

WRITE CYCLE1 (1)



WRITE CYCLE2 (1,6)



NOTES:

1. $\overline{WE}$ must be high during address transitions.
2. The internal write time of the memory is defined by the overlap of $\overline{CE}$ and $\overline{WE}$ low. All signals must be active to initiate a write and any one signal can terminate a write by going inactive. The data input setup and hold timing should be referenced to the second transition edge of the signal that terminates the write.
3. T_{WR} is measured from the earlier of $\overline{CE}$ or $\overline{WE}$ going high at the end of write cycle.
4. During this period, DQ pins are in the output state so that the input signals of opposite phase to the outputs must not be applied.
5. If the $\overline{CE}$ low transition occurs simultaneously with the $\overline{WE}$ low transitions or after the $\overline{WE}$ transition, output remain in a high impedance state.
6. $\overline{OE}$ is continuously low ($\overline{OE}$ = V_{IL}).
7. D_{OUT} is the same phase of write data of this write cycle.
8. D_{OUT} is the read data of next address.
9. If $\overline{CE}$ is low during this period, DQ pins are in the output state. Then the data input signals of opposite phase to the outputs must not be applied to them.
10. Transition is measured $\pm$500mV from steady state with C_L = 5pF as shown in Figure 1B. The parameter is guaranteed but not 100% tested.
11. T_{CW} is measured from the later of $\overline{CE}$ going low to the end of write.
12. The change of Read/Write cycle must accompany with $\overline{CE}$ or address toggled.

■ ORDERING INFORMATION

BS616LV1013 X X Z Y Y

SPEED
70: 70ns

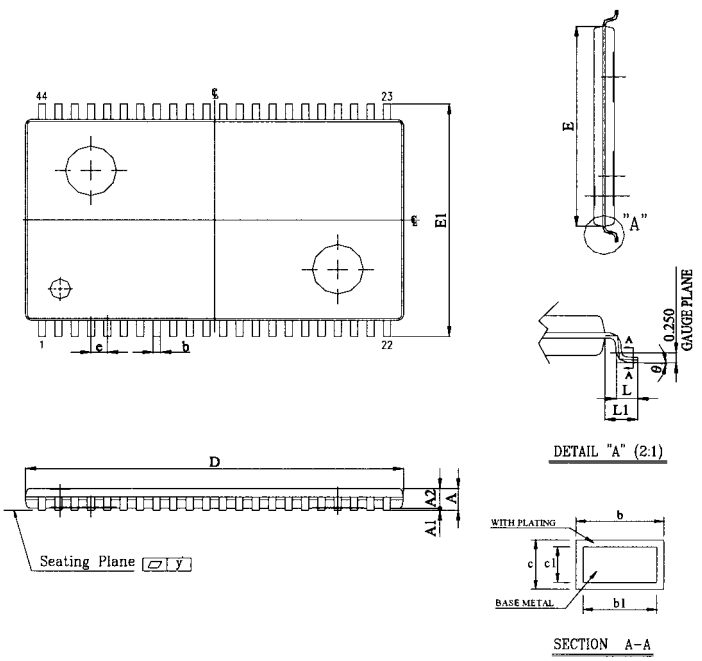
PKG MATERIAL
-: Normal
G: Green
P: Pb free

GRADE
C: +0°C ~ +70°C
I: -40°C ~ +85°C

PACKAGE
E: TSOP2-44
A: BGA-48-0608

Note:
BSI (Brilliance Semiconductor Inc.) assumes no responsibility for the application or use of any product or circuit described herein. BSI does not authorize its products for use as critical components in any application in which the failure of the BSI product may be expected to result in significant injury or death, including life-support systems and critical medical instruments.

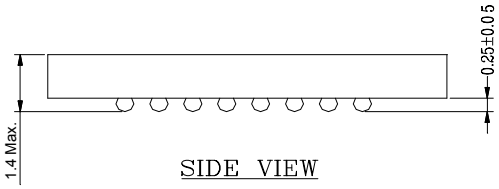
■ PACKAGE DIMENSIONS



SYMBOL \ UNIT	INCH	MM
A	0.0433± 0.004	1.10± 0.10
A1	0.004± 0.002	0.10± 0.05
A2	0.039± 0.002	1.00± 0.05
b	0.012 ~ 0.018	0.30 ~ 0.45
b1	0.012 ~ 0.016	0.30 ~ 0.40
c	0.005 ~ 0.008	0.12 ~ 0.21
c1	0.005 ~ 0.006	0.12 ~ 0.16
D	0.725± 0.004	18.41± 0.10
E	0.400± 0.004	10.16± 0.10
E1	0.463± 0.008	11.76± 0.20
e	0.0315± 0.004	0.80± 0.10
L	0.0197± 0.004	0.50± 0.10
L1	0.0315± 0.004	0.80± 0.10
y	0.004 Max.	0.1 Max.
θ	0° ~ 8°	0° ~ 8°

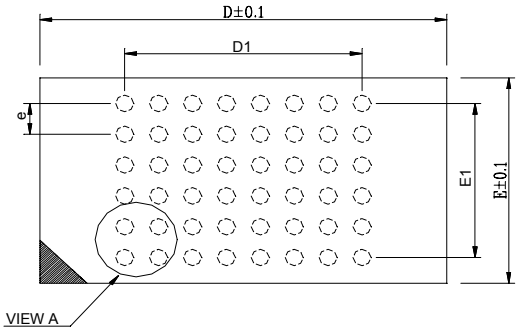
TSOP2-44

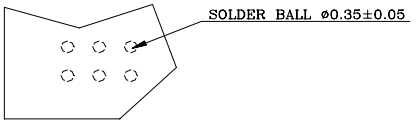
■ PACKAGE DIMENSIONS (continued)



NOTES:
1: CONTROLLING DIMENSIONS ARE IN MILLIMETERS.
2: PIN#1 DOT MARKING BY LASER OR PAD PRINT.
3: SYMBOL "N" IS THE NUMBER OF SOLDER BALLS.

BALL PITCH e = 0.75				
D	E	N	D1	E1
8.0	6.0	48	5.25	3.75





48 mini-BGA (6 x 8)